

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination CROUCH ET AL.	
		Examiner Jay M. Patidar	Art Unit 2862	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Mandal et al., The effects of defect depth and bending stress on magnetic Barkhausen noise and flux-leakage signals, J. Phys. D: Appl. Phys, 30, 1997, pages 1976-1983
	V	Crouch et al., IN-LINE STRESS MEASUREMENT BY THE CONTINUOUS BARKHAUSEN METHOD, Proceedings of IPC 2004, IPC 04-0233, October 4-8, 2004, pages 1-7
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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